E lectrical transport through a single-electron transistor strongly coupled to an oscillator

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We investigate electrical transport through a single-electron transistor coupled to a nanom echanical oscillator. Using a combination of a master-equation approach and a numerical M onte C ando m ethod, we calculate the average current and the current noise in the strong-coupling regime, studying deviations from previously derived analytic results valid in the limit of weak-coupling. A fter generalizing the weak-coupling theory to enable the calculation of higher cum ulants of the current, we use our numerical approach to study how the third cum ulant is a ected in the strong-coupling regime. In this case, we nd an interesting crossover between a weak-coupling transport regime where the third cum ulant heavily depends on the frequency of the oscillator to one where it becomes practically independent of this parameter. Finally, we study the spectrum of the transport noise and show that the two peaks found in the weak-coupling limit merge on increasing the coupling strength. O ur calculation of the frequency-dependence of the noise also allow s to describe how transport-induced dam ping of the mechanical oscillations is a ected in the strong-coupling regime.

I. IN TRODUCTION

N ano-electrom echanical devices, i.e., nanostructures in which electric transport through a device is in uenced by its mechanical degrees of freedom and vice versa, have attracted a lot of interest recently.^{1,2} On the one hand, these devices are promising for applications like sensors or ultra-sensitive mass detectors. On the other hand, they have opened up new directions in fundam ental research, with projects to cool nanom echanical system s to the quantum lim it.^{3,4}

The nanom echanical properties of single-electron transistors (SETs) are of particular interest in this context. The central island of a SET may be allowed to mechanically move between the two leads, such that electrons can tunnel on the island if the island has approached one lead and leave it again once it has mechanically moved to the other lead. These \shuttles" have been investigated in great detail.^{5,6,7,8,9,10,11,12,13} A nother possibility to couple the electrical and mechanical properties of the device is to design the SET such that its capacitive coupling to the gate depends on the displacem ent of a mechanical oscillator. Thus, mechanical degrees of freedom of the system may strongly in uence the current-voltage characteristics, current noise, and higher cumulants of the current. 14,15,16,17,18,19,20 It has been shown that the Coulomb blockade peaks are split for harm onic oscillations and are broadened by therm alloscillations. Know edge of the SET transport properties therefore allow sone to determ ine the characteristics of the oscillator, such as its amplitude and frequency. In such systems, electron tunneling through the island also has an e ect on the motion of the oscillator. This back-action leads to uctuations in the oscillator position and to dam ping.²¹

P ractical in plem entations of oscillator-coupled SET transistors can be realized by combining nanostructured silicon resonators with m etallic SET s. 22,23 A nother possi-

bility is to build SETs from suspended carbon nanotubes that act as quantum dots.²⁴ Quite recently, mechanical oscillations of the nanotube in such a device have been directly observed.²⁵

In the follow ing, we will consider a SET transistor coupled to a classical harm onic oscillator. This system has already been studied extensively.^{14,15} However, previous studies investigated the regime where the coupling between the oscillator and the SET is weak and the question what happens when the coupling is increased is still of great theoretical interest,²⁶ even if this regime is not readily accessible in the current generation of experiments. In this article, we will use a combination of a master-equation approach and a numerical M onte C arbo procedure to calculate the electrical current and its second and third cumulants and study how they are m odi ed by coupling to the oscillator, in the regime where the coupling is strong. W e will also study the frequency dependence of the transport noise.

The paper is organized as follows: in Section II, we discuss the system and the model whose strong-coupling lim it will be studied in the subsequent sections. The model and the master-equation approach that we use follow closely Ref. 14. This section also introduces the in portant dimensionless coupling parameter that is the ratio of the typical mechanical energy scale and the source-drain voltage. In the next section, Sec. III, we calculate the probability distributions of the position of the oscillator if the SET is in state N or N + 1 using a num erical M onte C arlo procedure. The G aussian form predicted by the weak-coupling approach is modi ed dramatically in the strong-coupling regime. In Section IV, we calculate the average current through the device at the charge-degeneracy point of the SET at which the current is maximal and discuss the deviations from the weakcoupling results. Finally, in Sections V and VIwe extend our studies to the current noise and the third cum ulant of the current.

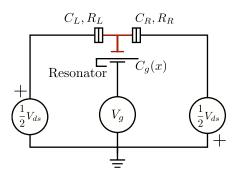


FIG.1: Circuit diagram of the system studied. The gate capacitance of the SET depends on the displacement of a mechanical oscillator, leading to a coupling of the electrical transport through the device and the mechanical motion of the oscillator.

II. COUPLED SET-OSCILLATOR SYSTEM DESCRIPTION

To describe the coupled SET -nanom echanical oscillator system, we use the form alism introduced in Ref. 14.

The system that we consider is shown in Fig. 1 in a schematic way and consists of two symmetric tunnel junctions, each with resistance R and capacitance C, connected in series. Transport through the SET is described using the orthodox model, where only two charge states are considered and where the current arises only from sequential tunneling.^{27,28} In this case, transport is govemed by four tunneling rates _i where i = R; L is the lead index and = +; indicates the direction of the tunneling. In this work, we adopt the convention that the forward (+) direction, given by the polarity of the bias voltage, is from the right to the left lead. The tunneling rates can be calculated using Ferm i's golden rule and are a function of the di erence in free energy E of the system before and after a tunneling event

$$_{i} = \frac{1}{Re^{2}} E_{i} f(E_{i});$$
 (1)

where $f(x) = (1 e^{x=k_B T})^{1}$, with T the electronic tem perature. The energy di erences E_{i} are given by

$$E_{L}^{+} = E_{L} = eV_{ds} \frac{1}{2} + (2N - 2N_{g} + 1)\frac{E_{c}}{eV_{ds}}$$
$$E_{R}^{+} = E_{R} = eV_{ds} \frac{1}{2} - (2N - 2N_{g} + 1)\frac{E_{c}}{eV_{ds}};$$
(2)

where V_{ds} is the applied drain-source voltage, $E_c = e^2 = (2C + C_g)$ is the charging energy of the island and $N_g = C_g V_g = e$ is the optim al num ber of charges on the island. K nowing the di erent rates, the average current I owing through the SET can be calculated using

$$I=e = P_{N+1} {}^{+}_{L} P_{N} {}^{+}_{L} = P_{N} {}^{+}_{R} P_{N+1} {}^{+}_{R} ; \quad (3)$$

where $P_{N \ (N+1)}$ is the probability to nd the island in charge state N (N + 1) in the stationary lim it.

Our model of the SET remains valid as long as its charging energy $E_{\rm c}$ is large compared to the electronic therm alenergy $k_{\rm B}~T_{\rm e}$ and the source-drain bias $eV_{\rm ds}$. We will neglect second-order tunneling processes (cotunneling).

In this work, the nanom echanical oscillator is modeled as a single, classical, harmonic oscillator of frequency $!_0$. Introducing a time scale $_t = R = V_{ds}$ which has the physical meaning of an average time between tunneling events, we can use the dimensionless parameter

$$= !_{0 t} = !_{0} \frac{R e}{V_{ds}}$$
(4)

to compare the typical electrical and mechanical timescales.

A particular state of the oscillator is then represented by a position x and velocity $u \cdot W = choose x = 0$ to be the equilibrium point of the oscillator when N charges are on the SET .W hen the charge state of the island is changed, for example, from N to N + 1, the change in the electrostatic forces between the oscillator (kept at constant potential V_q) and the SET e ectively shifts the equilibrium position of the resonator. The distance between the equilibrium positions when N and N + 1 charges are on the island de nes a natural length-scale x₀ of the prob- $2E_cN_q = (m!_0^2d)$. Here, d is the distance sep- $\lim \mathbf{x}_0 =$ arating the oscillator's equilibrium position and the SET island, such that the gate capacitance depends on x like $(d + x)^{1}$ C_a (x) 1 x=d. From now on, we will also use dim ensionless rates, i.e., all the rates will be given in units of 1^{1} .

Coupling a SET and a nanom echanical oscillator system is readily done by using the oscillator itself as the SET's gate. In this con guration, the capacitive coupling between the oscillator and the SET depends on the distance between them and by extension on the oscillator's position, e ectively allowing one to monitor the dynamics of the oscillator via the SET. As long as the am plitude of the oscillations around its equilibrium position is small compared to the distance d separating the oscillator and the SET island, the gate capacitance C_g(x) can be treated as linear in x. As a consequence, we obtain position-dependent dimensionless tunneling rates of the form

where the coe cients 29

$${}_{\rm L} = \frac{1}{2} + (2N \qquad 2N_{\rm g} + 1) \frac{{}_{\rm E}{}_{\rm c}}{{}_{\rm eV_{\rm ds}}} \qquad N$$

$${}_{\rm R} = \frac{1}{2} \quad (2N \qquad 2N_{\rm g} + 1) \frac{{}_{\rm E}{}_{\rm c}}{{}_{\rm eV_{\rm ds}}} + N \qquad (6)$$

are the position-independent part of the full dimension-less rate $_{i}$ (x) that full $_{L}$ + $_{R}$ = 1, and

$$= m ! {}_{0}^{2} x_{0}^{2} = (eV_{ds})$$
(7)

is a dimensionless coupling parameter that will play an important role in the following. Note that $_{\rm L}$, $_{\rm R}$ can become negative in the strong-coupling limit. The average dimensionless current in the presence of position-dependent rates can be calculated as an average of the dierent rates weighted by the probability to not the oscillator at a position x:

with $P_{N (N+1)}(x)$ the probability to nd the oscillator at position x while the island charge state is N (N + 1).

In the zero-tem perature lim it, the Ferm i functions in Eqs. (5) are in fact Heaviside step functions that determ ine the possible transport direction as a function of the position of the oscillator. Indeed, at zero tem perature, $x^{L} = {}_{L} x_{0} = and x^{R} =$ $_{R} x_{0} = de ne points where$ the current direction at lead L and R changes sign. For x^{R} < x current in the right junction can only be directed towards the island while in the opposite case only charge transfer from the island to the right lead is possible. Equivalently, transfer through the left junction is allowed from the island to the lead if $x < x^{L}$ and from the lead to the island otherwise. It is interesting to note that transport can be blocked altogether via this mechanism. For example, if N + 1 electrons are on the island and the oscillator is in position $x > x^{L}$, transport of the extra charge from the island to any lead is e ectively forbidden, our choice of bias direction in posing $x^{R} < x^{L}$.

The canonical way of dealing with an SET in the sequential tunneling regime is to introduce a master equation for the di erent charge states of the island. If the oscillator is coupled to a nanom echanical oscillator, such a simple master equation cannot be written, since the tunneling rates depend on the stochastic evolution of the oscillator. Following Ref. 14 we can introduce the probability distributions $P_N(x;u;t)$ and $P_{N+1}(x;u;t)$ to nd at a time t, the oscillator at position x;u in phase space and the SET in charge state N and N + 1 respectively and derive a master equation for these new objects:

$$\frac{\theta}{\theta t} P_{N} (x;u;t) = \frac{1}{2} \frac{\theta}{2} x \frac{\theta}{\theta u} P_{N} (x;u;t) \qquad u \frac{\theta}{\theta x} P_{N} (x;u;t) + \frac{1}{L} (x) + \frac{1}{R} (x) P_{N+1} (x;u;t) + \frac{1}{R} (x) + \frac{1}{L} (x) P_{N} (x;u;t);$$
(9a)

$$\frac{\theta}{\theta t} P_{N+1}(x;u;t) = \frac{1}{2} (x - x_0) \frac{\theta}{\theta u} P_{N+1}(x;u;t)$$

$$\frac{\theta}{\theta u} \frac{P_{N+1}(x;u;t)}{u + x}$$

$$\frac{\theta}{u + x} (x) + \frac{\theta}{u} (x;u;t)$$

$$\frac{\theta}{u + x} (x) + \frac{\theta}{u} (x) P_{N+1}(x;u;t)$$

$$\frac{\theta}{u + x} (x) + \frac{\theta}{u} (x) P_{N}(x;u;t) : (9b)$$

As pointed out in Ref. 14, when the coupling between the oscillator and the SET is weak (1) and when the gate voltage V_g is such that the system is tuned far from the C oulom b-blockade region, one can make the approximation that x^L ! 1 and x^R ! 1 and then write the tunneling rates as

$${}^{+}_{L}(x) = {}_{L} \frac{x}{x_{0}}; {}_{L}(x) = 0;$$

$${}^{+}_{R}(x) = {}_{R} + \frac{x}{x_{0}}; {}_{R}(x) = 0:$$
(10)

This weak-coupling form of Eq. (5) e ectively corresponds to neglecting any back-currents and the possibility of position-induced current blockade. However, the master equation is then simple enough to allow analytical solutions.

In this work, we will not study the e ect of extrinsic damping (i.e., a nite quality factor of the oscillator) and of nite temperatures, since they were discussed extensively in Refs. 14,15.

III. DYNAM ICS OF THE OSC ILLATOR IN THE STRONG -COUPLING REGIME

In the weak-coupling lim it 1, it was found¹⁴ that the interaction between the SET and the oscillator introduces an intrinsic damping mechanism. The damping, characterized by a decay rate = ² (in units of t¹) leads to a steady-state solution for the probability distributions $P_{N (N+1)}(x;u)$. In particular, the probability distributions $P_{N (N+1)}(x;u) = du P_{N (N+1)}(x;u)$, from which one can calculate the average current, have been shown to be well approximated by G aussians centered at x = 0 and $x = x_0$ for P_N and P_{N+1} , respectively.

O ne of the main goals of this work is to study deviations from the weak-coupling behavior. W ithout the simpli cations possible for 1 leading to Eq. (10), the stationary probability distributions $P_{N-(N+1)}(x;u)$ can no longer be investigated analytically and num erical methods must be used. In this work, we used a M onte C arb approach to simulate the stochastic nature of the SET-nanom echanical oscillator system in the parameter regime where the typical mechanical energy m $!_0^2 x_0^2$ is comparable to the bias energy eV_{ds} . D etails of our im – plem entation of the M onte C arb method are given in Appendix A.

We study the probability distribution of the oscillator in the charge-degenerate case, where $hP_N i = hP_{N+1}i$, where $hP_N i = dxP_N$ (x). At this point the current owing through the SET is maximal. In the presence of

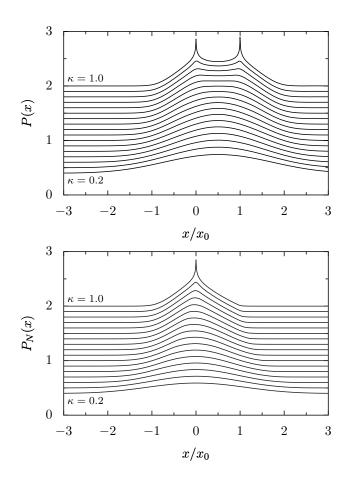


FIG. 2: Upper panel: Total probability distribution P (x) = $P_N(x) + P_{N+1}(x)$ of the oscillator's position for di erent values of the coupling constant (de ned in Eq. (7)). Lower panel: Probability distribution $P_N(x)$ to nd the oscillator at position x if the SET is in charge state N $\cdot P_{N+1}(x)$ can be obtained by the symmetry relation $P_{N+1}(x) = P_N(1=2 x)$. In both panels, lines are shifted for clarity by 2, and the di erence between neighboring curves is = 0.05. All calculations were done at = 0.3 and at the charge-degeneracy point. For the de nition of , see Eq. (4).

the oscillator, charge degeneracy is reached when $_{\rm L} = 1=2+$ =2. This relation, exact in the weak-coupling limit, has been empirically veri ed over the whole range of studied. In the weak-coupling limit, this relation can be shown using hP_{N+1}i = $_{\rm R}$ familiar from 2-state SETs. In our case, at the degeneracy point symmetry considerations in pose hxi = $x_0=2$ and the position dependence of the rate $_{\rm R}^+$ (x) must be taken into account, such that hP_{N+1}i = $\frac{1}{2}$ = $_{\rm R}$ + hx=x₀i. This electively corresponds to hP_{N+1}i = $_{\rm L}$ =2.

As can be seen from Fig.2, as is increased, the stationary position probability distribution evolves continuously from the weak-coupling Gaussian form to a distribution showing two sharp peaks at x = 0 and $x = x_0$ in the limit where = 1. This evolution is the result of a sharpening of each of the two subdistributions

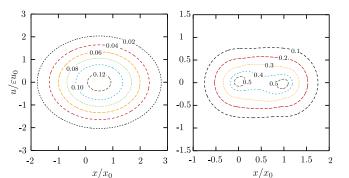


FIG.3: Two-dimensional phase-space distributions P (x;u) = $P_N(x;u) + P_{N+1}(x;u)$, for = 0.2 (left panel) and = 0.9 (right panel).

 $P_{N\ (N\ +\ 1)}\left(x\right)$ around their equilibrium position when is increased, allowing one to resolve the two subdistributions individually. This should not only be seen as natural consequence of the fact that the typical distance x_0 scales like $\overset{-}{-}$. In fact, the main cause of the appearance of the two sharp peaks is that small amplitude oscillations about each of the two equilibrium points become very stable when is increased.

We also note that the qualitative shape of each subdistribution evolve when is increased. While at low coupling the subdistribution $P_N(x)$ (resp. $P_{N+1}(x)$) is symmetric about x = 0 (resp. $x = x_0$), this is not the case for & 0.4. This asymmetry arises only at higher coupling since for low , the probability to nd the oscillator at $x < x^R$ or $x > x^L$ is negligible. When & 0.4, the probability of the oscillator being in a region transport is forbidden becomes in portant. Symmetry breaking arises since these regions are located only on one side of each equilibrium point.

Finally, we note that the important changes in $P_{N-(N+1)}(x)$ that accompany a variation in are also seen in the stationary velocity subdistributions $P_{N-(N+1)}(u) = duP_{N-(N+1)}(x;u)$, that approximatively follow $P_{N-(u=u_0)}$ ' $P_{N-(x=x_0)}$ and $P_{N+1}(u=u_0)$ ' $P_{N+1}((x-x_0)=x_0)$, where $u_0 = x_0 = t$ is the typical velocity scale in the problem. This can be seen in the two-dimensional phase-space distributions shown in Fig. 3, where both P (u) and P (x) are shown to become more peaked when is increased.

For > 1, our num erical investigations show that the current is strongly suppressed, rendering the intrinsic dam ping m echanism discussed at the beginning of this section ine ective. In this case, the system cannot be characterized by a steady-state probability distribution, and our m odel is not appropriate. Therefore, we only studied the parameter range 1.

A similar reasoning applies to Coulom b-blockade region, where the damping of the oscillator's motion is severely suppressed. However, numerically nding a steady-state solution close to the degeneracy point is pos-

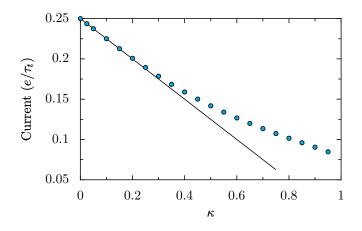


FIG.4:Current (in units of $e=_t$) as a function of at the degeneracy point hP_N i = hP_{N+1} i, for = 0.3. The dots are the results of the M onte C arb calculation and the solid line is the analytic form found within the weak-coupling approximation.

sible.

IV. AVERAGE CURRENT

The average current ow ing through the SET is closely tied to the oscillator's position distributions via the position-dependent tunneling rates. Consequently, one expects that the deviations from the weak-coupling behavior observed in P (x) = $P_N(x) + P_{N+1}(x)$ would a ect the current characteristics when is increased.

Just like in the previous section, we focus on the degeneracy point where the average charge state of the island is N + 1=2. At this point, the weak-coupling theory predicts¹⁴ that the current decreases linearly with increasing : I = $\frac{1}{4}$ (e= t). This decrease in the current can be explained in a qualitative way by the reduction of the overlap of the distributions $P_N(x)$ and $P_{N+1}(x)$ as the coupling is increased, each distribution becoming m ore localized around its equilibrium point, see Fig.2.

Figure 4 shows the average current as a function of . Like in the weak-coupling lim it, the localization of the di erent probability distributions around its equilibrium points leads to an overall decrease in the current when the coupling grows stronger. For & 0:3, how ever, we see that the num erical results deviate from the weakcoupling behavior: for stronger coupling the current is higher than the weak-coupling result. This can be explained using the rates given by Eq. (10). W hen either R_1 $A_X P_{N+1}$ or R_X^R is not negligible, these rates allow unphysical backward currents that are not present in the full master equation. For example, a point located at $x > x^{L}$ in the steady-state probability distribution $P_{N+1}(x;u)$ would contribute negatively to the average current when using the rates calculated within the weakcoupling approximation while it would not contribute to the current when taking into account the full expression

for the rates given in Eq. (6).

O ver the range of frequencies that we studied num erically (0:1 6 6 0:4), the current was found to be practically independent of for all but the strongest couplings (& 0:8). For instance, at = 0:9, the di erence between the calculated currents at = 0:1 and = 0:4 is on the order of a few percent.

V. NOISE AND HIGHER CUMULANTS IN THE STATIC REGIME

Originally, the interest in SETs was motivated by the suppression of the current in the Coulom b-blockade regime and the high sensitivity of the current to small. variations of the gate voltage. How ever, it is clear that a complete description of the transport processes in these devices requires not only know ledge of the current, but also of current-current correlations like e.g., the current noise.^{30,31} Recently, higher-order correlations have also been studied both theoretically and experimentally in nanoscale devices, in the fram ework of full counting statistics (FCS) (see R ef. 32 for a collection of articles on this topic, and Ref. 33,34 for a description of FCS in the context of transport through SETs). The FCS approach consists in studying the probability distribution P_n (t₀) that n electrons are transferred through one lead of the SET within a time period t_0 , in the limit where t_0 is by far the longest time scale in the problem. The full inform ation about the transport properties is contained in the cum ulants of this distribution function, the st three of which are given by the average 1 = hni, the variance $_2 = hn^2 i$ hn^2 , and the skewness $_3 = h(n)$ hni)³i that measures the asymmetry of the distribution. For example, the current $I = ehn i=t_0$ is proportional to the m ean of this distribution, while the zero-frequency shot noise power S (0) = $2e^2_2 = t_0$ is determined by its second cum ulant.

In this section, we study in detail the second and third cum ulants of the probability distribution function P_n (t₀) in the case of a coupled SET -nanom echanical system .

A. W eak-coupling case

It is instructive to start by considering the weakcoupling case 1, since in this regime we can calculate the noise and higher cumulants without resorting to M onte C arlo simulations by solving directly for $\ln^i(t_0)$ i in the long-time limit (t_0 1). In this section, we generalize the work that was done in R ef. 15 where a m ethod to calculate the current-noise using the m om ents of the steady-state probability distribution $P_N(N+1)(x;u)$ of the oscillator in phase space was described. In this approach, the current-noise is calculated from the solution of the equation of m otion of $\ln^2(t)$ i, the average square of the number of charges that went through a lead in a time t. Here, we extend this method for the calculation of higher cum ulants by deriving the equation of m otion for the general quantity hn^m (t) i from which the m th cum ulant can be extracted.

To proceed, we write a master equation for the probability $P_{N}^{n}(N+1)(x;u;t)$ to nd, at time t, the oscillator at position x with velocity u, the island being in charge state N (N + 1), and that n charges having passed through a lead of the SET in the interval [0;t]. We will again make the assumptions leading to Eq. (10). Considering for de nitiveness the left lead, at zero temperature and neglecting any extrinsic damping, one nds^{15}

$$\frac{\theta}{\theta t} P_{N}^{n}(x;u;t) = \frac{1}{2} \frac{2}{\pi} \frac{\theta}{\theta u} P_{N}^{n}(x;u;t) \qquad u \frac{\theta}{\theta x} P_{N}^{n}(x;u;t) + \frac{1}{L}(x) P_{N+1}^{n-1}(x;u;t) \qquad \frac{\theta}{R}(x) P_{N}^{n}(x;u;t);$$

$$(11a)$$

$$\frac{\theta}{\theta t} P_{N+1}^{n} (x; u; t) = \frac{1}{2} (x - x_{0}) \frac{\theta}{\theta u} P_{N+1}^{n} (x; u; t)$$

$$u \frac{\theta}{\theta x} P_{N+1}^{n} (x; u; t)$$

$$\frac{\theta}{L} (x) P_{N+1}^{n} (x; u; t) + \frac{\theta}{R} (x) P_{N}^{n} (x; u; t) :$$
(11b)

where the rates are taken from Eq. (10). Dening the coupled moments $hx^j u^k n^m$ i and $hx^j u^k n^m$ $i_{N\,+\,1}$ as

$$\begin{array}{cccc} m^{m} \mathbf{x}^{j} u^{k} \mathbf{i} = \\ \mathbf{X} & \mathbf{Z} & \mathbf{Z} \\ n^{m} & \mathrm{d} \mathbf{u} & \mathrm{d} \mathbf{x} \mathbf{x}^{j} u^{k} \mathbf{P}_{N}^{n} \left(\mathbf{x}; \mathbf{u}; \right) + \mathbf{P}_{N+1}^{n} \left(\mathbf{x}; \mathbf{u}; \right) ; \\ \end{array}$$

$$(12a)$$

one can calculate the equation of motion for these quantities using Eq. (11). W ith x in units of x_0 and u in units of u_0 , one nds

$$\frac{d}{d} hx^{j} u^{k} n^{m} i_{N+1} = k^{2} hx^{j+1} u^{k-1} n^{m} i_{N+1} hx^{j} u^{k-1} n^{m} i_{N+1} + j hx^{j-1} u^{k+1} n^{m} i_{N+1} hx^{j} u^{k} n^{m} i_{N+1} + R hx^{j} u^{k} n^{m} i + hx^{j+1} u^{k} n^{m} i;$$
(13a)

$$\frac{d}{d}hx^{j}u^{k}n^{m}i = k^{2}hx^{j+1}u^{k-1}n^{m}i hx^{j}u^{k-1}n^{m}i_{N+1} + jhx^{j-1}u^{k+1}n^{m}i + jhx^{j-1}u^{k+1}n^{m}i + \frac{^{n}X^{-1}}{_{i=0}}m_{L}hx^{j}u^{k}n^{i}i_{N+1} hx^{j+1}u^{k}n^{i}i_{N+1} :$$
(13b)

Here, averages that are independent of n (averages of the form $hx^{j}u^{k}n^{0}i$) are tim e-independent and can be evaluated in the stationary limit, i.e., Eqs. (13a-13b) can be used to generate a closed linear system of equations.³⁵ The term $shx^{j}u^{k}i$ of order j+k=c are connected to the term $shx^{j}u^{k}i_{N+1}$ of order j+k=c 1. This means that to solve for a moment $hx^{j}u^{k}i$, we must use the c+1 equations of the type of Eq. (13b) where j+k=c 1. This means that to calculate any moment of the form $hx^{j}u^{k}i$ and $hx^{j}u^{k}i_{N+1}$. Know ledge of $hx^{j}u^{k}i$ enables one to calculate the long-time behavior of the coupled moments of the charge and oscillator's position in phase space $hx^{j^0}u^{k^0}n^{i}i$, and thus the i-th moment $\ln^{i}i$ of P_n .

The ratio of the zero-frequency shot noise power and the average current (times 2e), or equivalently, the ratio of the second and rst cumulants of P_n is called Fano factor and is readily calculated using this approach. Since it shows a complex dependence on the coe cients $_{\rm L}$, $_{\rm R}$, and on the parameters and , it is convenient to expand the result in powers of . Introducing a parameter de ned via = $_{\rm L}$ (1 +)=2 (or, equivalently, = $_{\rm R}$ + (1)=2) that measures the difference between $_{\rm L}$ and its value at the degeneracy point, one can write down the Fano factor in a way that underlines its symmetry with respect to this point:

$$\frac{S(0)}{2eI} = \frac{1}{2} + 2^{2} + 4^{2} + 6^{2} 2^{2} + \frac{1}{2} + 2^{2} \frac{1}{2} + 2^{2} \frac{2}{2} + 0(3);$$
(14)

For 1, the Fano factor is dom inated by the term $= {}^{2}$, like in the case where one considers a system of two SETs coupled by an oscillator.³⁶ F inally, we note that current conservation in plies that the Fano factor is identical in both leads.³⁷

Equation 13 is one of the main result of our article, as it allows for the calculation of higher cumulants of the current by integrating the equation of m otion for the moments of the form $hx^{j}u^{k}n^{m}$ (t) iw ith m > 0. For exam ple, we calculated the norm alized third cumulant 3=hni of P_n (t₀). The results are presented in Fig. 5. W e stress that these results have been obtained by integrating the equation motion for hn³ (t) i valid in the weak-coupling regime and not via a Monte Carlo simulation. Starting from the value 1=4 at = $0_{,33}^{33}$ the norm alized third cumulant decreases rapidly when is increased. On further increase of , it reaches a minimum at an -dependent value of . The inset of Fig. 5 shows that the leading contribution to the norm alized third cum ulant in the weakcoupling regime is of the form 4. As a consequence, we note that the asym metry of the probability distribution P_n that is determined by $_3$, can electively be tuned by changing the frequency of the oscillator or $\ _{\rm t}.$ The scaled quantity 4 3=hni shows contributions of higherorder corrections in to the norm alized third cum ulant.

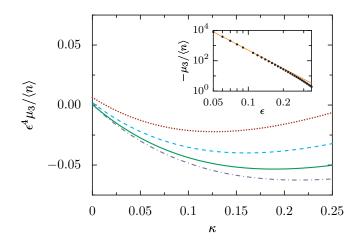


FIG. 5: Normalized third cumulant as a function of for di erent values of , as calculated within the weak-coupling approximation and scaled by ⁴. Dotted line: = 0.4, dashed line: = 0.3, solid line: = 0.2, dash-dotted line: = 0.1. The inset shows the -dependence of the normalized third cumulant at = 0.1 (symbols), as calculated within the weakcoupling approximation. The solid line is a t to a power law ⁴. These results were obtained by integrating the equation of motion for hn³ (t) i following from Eq. (13).

B. Higher coupling

It is unfortunately not straightforward to generalize the previously described method for calculating the cumulants of P_n outside the weak-coupling regime. The presence of x-dependent Ferm i functions in the tunneling rates as well as the possibility of charge ow against the direction set by the bias voltage due to the position of the oscillator gives rise to a system of equations that is not closed and cannot be solved analytically. Even if we neglect transport against the dom inant direction of the current _j (x) ' 0, but keep the position dependence of the Ferm i distributions in $\frac{1}{j}$ (x), it is still not possible to derive a system of equations coupling only objects of the form $hx^{j}u^{k}n^{m}$ i. Therefore, we will use a numerical approach to evaluate the cum ulants of P_n.

Indeed, the M onte C arlo m ethod described in Appendix A can be used to measure the FCS of electron transport in the same way as it can be done in experiments.³⁸ A very long M onte C arlo run is divided into intervals of duration t_0 ¹, here, = ² is the damping constant de ned at the beginning of Sec. III;

 $^1\,$ is the longest intrinsic tim e scale of the problem . By counting the num ber of charges going through one lead during each interval, one can reconstruct the probability distribution P $_n$ (t_0), and from it calculate the cum ulants.

W e study current correlations at the charge degeneracy point, where the average charge state of the island is N + 1=2. The top panel of F ig. 6 com pares the weakcoupling Fano factor to the num erical M onte C arlo results for di erent values of the coupling parameter .

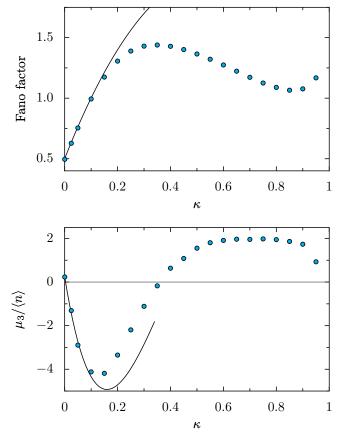


FIG.6: Upper panel: Fano factor as a function of at the degeneracy point $hP_N i = hP_{N+1}i$. The dots are the results of the numerical calculation and the solid line is the analytic form found within the weak-coupling approximation. Lower panel: Normalized third cumulant $_3$ of the probability distribution P_n . For both panels, = 0.3.

Naturally, for . 02, the agreem ent between the num erical results and those obtained analytically is very good. Beyond this point, the num erically calculated Fano factor shows an interesting non-monotonic behavior, with a maximum at 0:35 and a minimum at 0:85. The lower panel of Fig. 6 also shows the evolution of the norm alized third cum ulant of P_n, giving the asymmetry of this probability distribution about its mean hni. Starting from the = 0 value of 1=4 derived for a sim ple SET device, our results show that this quantity is, in the weak-coupling lim it, very sensitive to variations of . Indeed, the norm alized third cum ulant changes sign twice in the region 0.35, reaching a maximum value approximatively in the middle of this region. This contrasts with the strong-coupling behavior: $_3$ =hni stays practically constant for 0:5. . 0:9.

W e will now address the question how the previous results are modi ed when changing the frequency of the oscillator. Figure 7 shows the dependence of the Fano factor and the normalized third cum ulant as a function of for di erent values of . First, we note that the

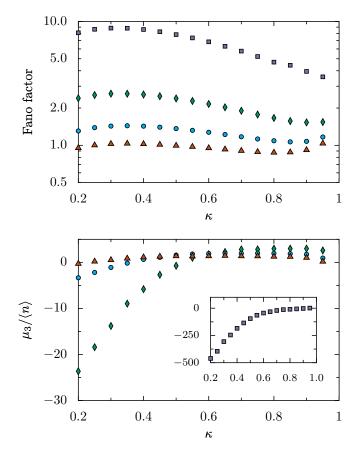


FIG. 7: Fano factor (upper panel) and normalized third cumulant (lower panel and inset) as a function of for dierent values of : = 0:1 (squares in the upper panel and in the inset), = 0:2 (diam onds), = 0:3 (circles), and = 0:4 (triangles). Note the logarithm ic y-axis in the upper panel.

actual value of the Fano factor is increased dram atically for low eroscillator frequencies, as expected from the term

=² that dom in the low -frequency regime. In the weak-coupling region (.03), the magnitude of the norm alized third cum ulant is also heavily a ected by a change in frequency, in agreem entwith the weak-coupling ⁴. Despite these major leading order dependence changes in magnitude of both the Fano factor and the norm alized third cum ulant, the overall qualitative e ect of an increase in coupling does not seem to depend heavily on , in the frequency range we investigated. In particular, the position of the maximum in the Fano factor rem ains constant. A lso, the norm alized third cum ulant always shows a change of sign, albeit at an -dependent value of , and goes to a positive for ! 1. Rem arkably, the value of the norm alized third cum ulant is much less sensitive to in the strong-coupling regime. This might be the signature of a transport regime in the ! 1 region that is radically di erent of the one found for ' 0.2.

VI. FREQUENCY-DEPENDENT NO ISE

In systems that exhibit internal dynamics like the one we study, it is especially interesting to look at the frequency-dependence of the current-current correlations. In Ref. 15, the frequency-dependent noise S (!) of a SET weakly coupled to a nanom echanical oscillator was thoroughly studied. It was found that, the noise spectrum shows only two peaks at nite frequency at $!_0^0$ and $2!_0^0$, where $!_0^0 = !_0^{-1}$ is the electrive frequency of the damped harmonic oscillator. In this section, we extend the work of Ref. 15 by studying the frequency-dependent noise power S (!) in the strong-coupling regime (02. < 1).

In order to calculate the frequency-dependent noise using our M onte C arlo m ethod, we follow the approach developed by M adD onald^{31,39} that was used recently to study the noise properties of m esoscopic systems, including coupled SET -nanom echanical systems in the weak-coupling regime. In general, the current-noise power at junction a is de ned as the Fourier transform of the current autocorrelation function K _{iji} at junction i,

$$S_{i;i}(!) = 2$$
 d $cos(!) K_{i;i}();$ (15)

where

$$K_{i;i}() = hI_i(t+)I_i(t)i hI_i^2$$
: (16)

To proceed with the M acD onald approach, $I_{\rm i}$, and therefore $I_{\rm i}$ hIi, must be assumed to be statistically uctuating variables, such that the autocorrelation function K $_{\rm i;i}$ is independent of t. In this case, the M acD onald form ula relates the uctuation n about the average of the number of charges n that went through a junction in time ,

$$n_{i}() = n_{i}()$$
 $h_{i} = \frac{Z_{t+}}{t}$ $dt^{0} I_{i}(t^{0})$ $h_{i} = \frac{T_{t+}}{t}$ (17)

to the current-noise power via

$$S_{i,i}(!) = 2! d sin(!) \frac{2}{0}h(n_i())^2 i;$$
 (18)

where $h(n_i())^2 i = hn_i^2() i$ $hI_i i^2$. Since $hn^2() i$ and $hI_i i$ are easily accessible through the M onte C arb simulation, S(!) can be calculated by taking a numerical time-derivative of $h(n_i())^2 i$ and then evaluating the Fourier sine-transform. Note that we consider only the particle current uctuations here. The electrical current noise at nite frequencies includes a contribution from displacement currents, which depend on the capacitive couplings between the island and the leads.³⁷ Since we assume that our frequencies of interest are much smaller than the relevant RC-frequencies, we can neglect the displacement currents here, see e.g. the discussion in Ref. 40,41.

The results of the M onte C arb simulation are shown in Fig. 8. Like in the weak-coupling case, S (!) shows

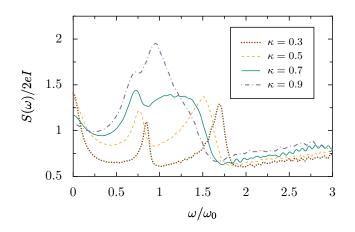


FIG. 8: Frequency-dependent noise power beyond the weakcoupling approximation. For each curve, the SET is tuned to the charge-degeneracy point and = 0.3.

twomain nite-frequency features. Surprisingly, even for strong coupling, we do not nd any features for frequencies higher than $2!_0$. We nd a low -frequency peak that de nes the frequency $!_0^0$ (which will be dierent from the weak-coupling prediction $!_0^{-1}$ in the general case). The second feature evolves from the peak located at $2!_{0}^{0}$ predicted by the weak-coupling theory. W hile both peaks are considerably broadened by an increase in the coupling strength, their respective shapes evolve in a qualitatively di erent way. W hereas the rst peak is shifted in absolute frequency, the second peak broadens in a very asym m etric way, with much of the weight shifting to lower frequencies. The slope of its left shoulder decreases with increasing until it forms a plateau at around 0**:**7.0n increasing even further, the two peaksm erge, leading to super-Poissonian frequency-dependent noise throughout the frequency range $! < 1:5!_0$.

Figure 9 shows the position of the maxima of the rst peak in the frequency-dependent noise power as a function of . By comparing the position of the rst peak extracted from the curves shown in Fig. 8 (data points in Fig. 9) to the weak-coupling prediction $!_0^0 = !_0^1$ (solid line in Fig.9), we nd quantitative agreement on ly for . 0.2. Beyond this point, the ratio $!_0^0=!_0$ still decreases, albeit slow ly, when is increased. It reaches a saturation value $!_0^0$ 0.7!₀ for & 0.7.

This behavior can be understood by interpreting the frequency shift in terms of an elective damping mechanism caused by electron tunneling. Since there is no damping without current, the natural modi cation of the weak-coupling damping constant $= 2^{\circ}$ in the strong-coupling regime is to renormalize the weak-coupling result by the probability P to nd the oscillator in a position where in principle current is allowed, i.e., for $x^{R} < x$ and charge state N, or $x < x^{L}$ and charge state N + 1. Dening a renormalized damping constant $s^{c} = P = 2^{\circ}$, it is possible to estimate the position of the rst peak as a function of using values of P extracted from curves

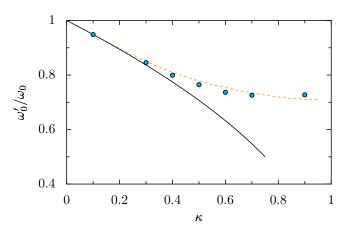


FIG. 9: Position $!_0^0$ of the rst peak in the frequency-dependent noise power as a function of . The solid line gives the weak-coupling prediction $!_0^{-1}$, the data points are the num erical M onte C arlo results, and the dashed line was obtained using an elective damping constant, see text.

presented in Fig. 2. The result is shown as the dashed curve in Fig. 9 and agrees with the data points obtained by the M onte C arlo m ethod in a quantitative way.

VII. CONCLUSION

In this paper, we have studied the strong-coupling lim it. of a SET transistor coupled to a classical harm on ic oscillator. W e have used a combination of a master-equation approach and a numerical Monte Carlo procedure to calculate the position distribution of the oscillator, the electrical current, and the zero-frequency noise in both the weak-coupling and strong-coupling regime. With increasing coupling, we found that the position distribution of the oscillator evolves from a broad Gaussian to a a function sharply peaked around each of the chargestate dependent equilibrium positions of the oscillator. W e found that the average current in the strong-coupling regime is higher than the value predicted by the weakcoupling theory and that the Fano factor varies in a nonm onotonous fashion when coupling is increased. W e have generalized the weak-coupling theory to allow the calculation of higher cum ulants of the current, and have presented results for the third cumulant. In the weakcoupling regime, the third cumulant was found to depend strongly on the frequency of the oscillator, whereas in the strong-coupling regime it becomes practically independent of this parameter. We have also studied the frequency-dependent transport noise. Even in the strongcoupling regime, there are no peaks for frequencies higher than 2! o, and the two peaks found in the weak-coupling lim it merge on increasing the coupling strength. Finally, we introduced a generalized expression connecting the dam ping rate in the strong-coupling regim e with the other param eters of our model and used it to understand

the evolution of the oscillator's damping-renormalized frequency as a function of coupling.

VIII. ACKNOW LEDGMENTS

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APPENDIX A:DETAILS OF THE MONTE CARLO APPROACH USED

M onte C arbo m ethods have been used for a long time to calculate num erically the transport properties of mesoscopic systems like SETs.⁴² W hen dealing with a simple SET system, the idea of the M onte C arbo approach is to solve the master equation for the charge states of the SET by discretizing time into small intervals and allow - ing charge transfer to and from the dot with a probability that is proportional to the tunneling rates and the time interval between two attempts.

If the SET is coupled to a harm onic oscillator, we can proceed in a similar way, by considering charge transfer attempts at a nite frequency $\begin{pmatrix} t \end{pmatrix}^1$, where 1 is a dimensionless step size. The success probability

for a charge transfer is calculated from the oscillator's position-dependent instantaneous rates $_{i}$ (x) calculated at the time of the attempt. Between di erent attempts, the oscillator's state evolves according to the classical equation ofm otion, whose solution depends on the charge state of the SET, the equilibrium position of the oscillator being shifted by x_0 when the charge state is changed from N ! N + 1 or by x_0 in the opposite case. At the beginning of each run, the state of the system is determined random ly from the stationary probability distributions P_N (x;u) and P_{N+1} (x;u). In practice, this can be implemented by using the nal state of the n-th run.

We consider runs of total time t_0 $_{\rm t}$, such that each run consists of M = $t_0=$ steps. Both the time scales t $_0$ $_{\rm t}$ and $_{\rm t}$ are chosen in a way such that increasing t_0 or decreasing does not a ect the value of the di erent physical quantities we extract from our calculation. In practice, this corresponds to choosing < 0.02 and t $_0$ $_{\rm t}$ an order of magnitude greater than the typical dam ping time 1= . A consequence of this last constraint is that the M onte C arlo approach is particularly useful in the strong-coupling regime, where the number of steps M per run can be kept relatively small, allowing for m ore runs to be m ade in the same am ount of com puter time.

We checked that our code reproduces the analytical results of Ref. 33 for the dependence of the noise and the third cumulant on the asymmetry coecients $_{\rm L}$ $_{\rm R}$ in the = 0 limit. Also, the probability distributions $P_{\rm N}$ (x;u) and $P_{\rm N+1}$ (x;u) that we calculate using the M onte C arb approach coincide with the results one nds when solving Eq. (9) on a grid.¹⁴

- ¹ A.C leland and M.R oukes, Nature 392, 160 (1998).
- ² M.P.Blencowe, Phys.Rep. 395, 159 (2004).
- ³ M.Roukes, Phys. W orld 14, 25 (2001).
- ⁴ M.LaHaye, O.Buu, B.Camarota, and K.Schwab, Science 304, 74 (2004).
- ⁵ L. Gorelik, A. Isacsson, M. Voinova, B. Kasemo, R. Shekhter, and M. Jonson, Phys. Rev. Lett. 80, 4526 (1998).
- $^{\rm 6}$ C.W eiss and W .Zwerger, Europhys.Lett. 47, 97 (1999).
- ⁷ A.Erbe, C.Weiss, W.Zwerger, and R.Blick, Phys.Rev. Lett. 87, 096106 (2001).
- ⁸ F.Pistolesi, Phys.Rev.B 69, 245409 (2004).
- ⁹ A. Isacsson and T. Nord, Europhys. Lett. 66, 708 (2004).
- ¹⁰ T.Novotny, A.Donarini, C.Flindt, and A.-P.Jauho, Phys. Rev.Lett. 92, 248302 (2004).
- 11 F.Pistolesi and R.Fazio, New J.ofPhys.8, 113 (2006).
- ¹² D.Fedorets, L.Y.G orelik, R.I.Shekhter, and M. Jonson, Phys. Rev. Lett. 92, 166801 (2004).
- ¹³ D.Fedorets, L.Y.G orelik, R.I.Shekhter, and M.Jonson, Phys. Rev. Lett. 95, 057203 (2005).
- ¹⁴ A.D.Amour, M.P.B Lencowe, and Y.Zhang, Phys.Rev. B 69, 125313 (2004).
- ¹⁵ A.D.Amour, Phys.Rev.B 70, 165315 (2004).
- $^{16}\,$ D . M ozyrsky, I. M artin, and M . B . H astings, P hys. Rev.

Lett. 92,018303 (2004).

- ¹⁷ N.M. Chtchelkatchev, W. Belzig, and C. Bruder, Phys. Rev.B 70, 193305 (2004).
- ¹⁸ C.Flindt, T.Novotny, and A.P. Jauho, Europhys. Lett. 69, 475 (2005).
- ¹⁹ O. Usmani, Y. M. B lanter, and Y. V. Nazarov, condmat/0603017 (2006).
- ²⁰ F. Haupt, F. Cavaliere, R. Fazio, and M. Sassetti, condmat/0607080 (2006).
- ²¹ A.Clerk, Phys. Rev. B 70, 245306 (2004).
- ²² A. C leland and M. Roukes, Appl. Phys. Lett. 69, 2653 (1996).
- 23 R.G.Knobeland A.N.Cleland, Nature 424, 291 (2003).
- ²⁴ S.Sapm az, Y.M. Blanter, L.G urevich, and H.S.J.van der Zant, Phys. Rev. B 67, 235414 (2003).
- ²⁵ V.Sazonova, Y.Yaish, H.U stunel, D.Roundy, T.A.A rias, and P.M cEuen, Nature 431, 284 (2004).
- ²⁶ M.P.Blencowe, Contem p.Phys. 46, 249 (2005).
- ²⁷ D. V. Averin, A. N. Korotkov, and K. K. Likharev, Phys. Rev. B 44, 6199 (1991).
- ²⁸ C.W.J.Beenakker, Phys.Rev.B 44, 1646 (1991).
- ²⁹ These coe cients were called L, R in Ref. 14. Since they are not rates (e.g., they can become negative in the strong-coupling lim it), we have chosen a di erent notation.

- ³⁰ S.Hersh eld, J.H.Davies, P.Hyklgaard, C.J.Stanton, and J.W.W ilkins, Phys. Rev. B 47, 1967 (1993).
- ³¹ A.Korotkov, Phys. Rev. B 49, 10381 (1994).
- ³² Y.V.Nazarov, Quantum Noise in Mesoscopic Physics (Kluwer, Dordrecht, 2003).
- ³³ D.A.Bagrets and Y.V.Nazarov, Phys.Rev.B 67, 085316 (2003).
- ³⁴ W.Belzig, Phys.Rev.B 71, 161301(R) (2005).
- ³⁵ These equations agree with the system of equations shown in the Appendix of R ef. 15; the factor k² displayed there is a typo and should read k.
- ³⁶ D.A.Rodrigues and A.D.Amour, Phys.Rev.B 72, 085324 (2005).

- ³⁷ Y.M.Blanter and M.Buttiker, Phys. Rep. 336, 1 (2000).
- ³⁸ S.Gustavsson, R.Leturcq, B.Sim ovic, R.Schleser, T.Ihn, P.Studerus, K.Ensslin, D.C.Driscoll, and A.C.Gossard, Phys. Rev. Lett. 96, 076605 (2006).
- ³⁹ D.K.C.M acD onald, Noise and uctuations: an introduction (W iley, New York, 1962).
- ⁴⁰ A.Cottet, W.Belzig, and C.Bruder, Phys. Rev. Lett. 92, 206801 (2004).
- ⁴¹ A.Cottet, W.Belzig, and C.Bruder, Phys. Rev. B 70, 115315 (2004).
- ⁴² M.Amman, K.Mullen, and E.Ben-Jacob, J.Appl.Phys. 65, 339 (1989).